

<b>Notice of References Cited</b>	Application/Control No. 09/825,434	Applicant(s)/Patent Under Reexamination CALLAHAN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,594,904 A	01-1997	Linnermark et al.	717/124
	B	US-6,055,492 A	04-2000	Alexander et al.	702/179
	C	US-5,903,730 A	05-1999	Asai et al.	709/224
	D	US-5,812,811 A	09-1998	Dubey et al.	712/216
	E	US-5,774,728 A	06-1998	Breslau et al.	717/141
	F	US-5,333,280 A	07-1994	Ishikawa et al.	712/241
	G	US-6,029,005 A	02-2000	Radigan, Jim J.	717/158
	H	US-6,549,930 B1	04-2003	Chrysos et al.	718/104
	I	US-5,724,565	03-1998	Dubey et al.	712/245
	J	US-6,094,716 A	07-2000	Witt, David B.	712/23
	K	US-4,819,234	04-1989	Huber, William S.	717/129
	L	US-5,428,618 A	06-1995	Ueki et al.	717/124
	M	US-5,898,873 A	04-1999	Lehr, Theodore Franklin	717/125

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Miller et al., A mechanism for efficient debugging of parallel programs, Nov 1988, ACM SIGPLAN, Vol. 24, pg.141-150
	V	Poulsen et al., Execution-driven tools for parallel simulation of parallel architectures and applications, ACM SIGPLAN, Dec, 1993, pg. 860-869
	W	Setia, Trace-driven analysis of migration-base gang scheduling policies for parallel computers, 1997, IEEE, pg. 489-492
	X	Kosoresow et al., Intrusion detectio via system call traces, 1997, IEEE, pg. 35-42

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,548,717 A	08-1996	Wooldridge et al.	717/124
	B	US-6,145,121 A	11-2000	Levy et al.	717/135
	C	US-6,282,701 B1	08-2001	Wygodyny et al.	717/125
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Tolujev et al., Assessment of simulation models base on trace file analysis: a metamodeling approach, Simulation conference proceedings, 1998, pg. 443-450
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.